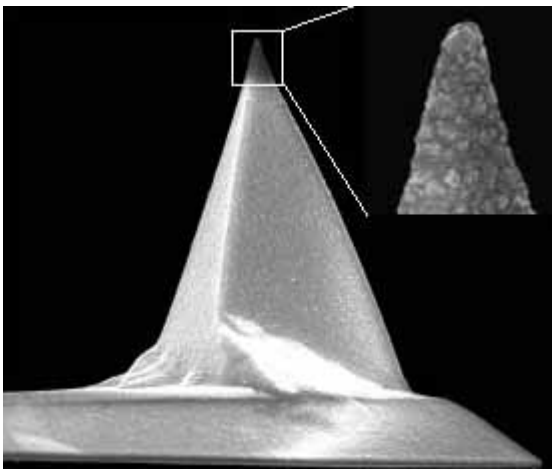
DD-ACTA

The DD-ACTA Probe offers a unique combination of hardness and conducting tip. The tip side of these probes is coated with polycrystalline diamond. The diamond film is in-situ doped with boron to make it highly conducting. The reflex side of the cantilever is coated with Aluminum. These probes are based on the Applied NanoStructures ACTA probes which are silicon probes designed for Non-Contact, Tapping Mode, Intermittent Contact, Close Contact and/or hard contact applications. These probes have a high frequency that allows for faster scanning speeds, and have Aluminum coating on the reflex side to increase laser signal quality.

Tip Specifications



- **Material**: Silicon
- **Shape**: Pyramidal
- **Height (µm)**: 14-16
- **Aspect ratio**: 1.5-3.0
- **ROC (nm)** : 100-300
- **Coating**: 100 nm Doped Diamond

DD-ACTA

On click zoom images

Download Spec

Cantilever Specifications

Material:Silicon
Shape :Rectangular
Reflex coating :Al, 50 nm ± 5

Parameter	Nominal	Min	Max
k (N/m)	40	25	75
f (kHz)	300.0	200.0	400.0
Length (µm)	125.0	115.0	135.0
Width (µm)	35.0	30.0	40.0
Thickness (µm)	4.50	4.00	5.00